Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	_
10/765,121	NIHEI ET AL.	
Examiner	Art Unit	
Jay M. Patidar	2862	

SEARCHED					
Class	Subclass	Date	Examiner		
324	207.2	12/12/2005	JP		
	207.21				
	207.25				
	174				
	166				
	173				
	178				
	179				
702	151				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEAR (INCLUDING SI	CH NOT EARCH S	ES STRATEGY))
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EAST searched.	:	12/12/2005	JP
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